

Magnetocrystalline anisotropy and magnetoelastic properties of the $Co_2Fe_{0.4}Mn_{0.6}Si$ (CFMS) and $Co_2FeGa_{0.5}Ge_{0.5}$ (CFGG) Heusler alloys films

<u>O.M. Chumak¹</u>, A. Nabiałek¹, R. Żuberek¹, I. Radelytskyi¹, T. Yamamoto², T. Seki^{2,3}, K. Takanashi^{2,3}, L. T. Baczewski¹, H. Szymczak¹

1 Institute of Physics, Polish Academy of Sciences, Warsaw, Poland 2 Institute for Materials Research, Tohoku University, Sendai, Japan 3 Center for Spintronics Research Network, Tohoku University, Sendai, Japan



The out-of-plane magnetocrystalline anisotropy and magnetoelastic properties of series of epitaxially grown layers of Co₂Fe₀₄Mn₀₆Si and Co₂FeGa₀₅Ge₀₅ Heusler alloys thin films deposited on MgO with chromium buffer layer were investigated by means of the ferromagnetic resonance (FMR), SQUID magnetometer, and by the strain modulated FMR technique. The magnitude of the magnetocrystalline anisotropy constant was found to decrease with increasing layer thickness. The change of the anisotropy is caused mainly by the surface effects. However, for some of the samples series, the change of chemical ordering with the change of the magnetic layer thickness was also observed. An additional silver buffer layer influence on the properties of the magnetic layer was also investigated. For all three of the investigated series of the Heusler alloys, i.e., CFMS without Ag, CFMS with Ag, and CFGG, the experimentally observed magnitude of the magnetoelastic constant increases with the increase of the magnetic layer thickness. [1]



MAGNETOELASTICITY AND MAGNETIC ANISOTROPY

• For MgO/Cr/CFMS/Au, MgO/Cr/Ag/CFMS/Au and

samples,

magnetostriction constants were determined.

improves with increase of the film thickness.

magnetocrystalline anisotropy, magnetoelastic, and

All the CFMS layer samples without Ag have similar

degree of chemical order. For CFGG and

Ag-buffered CFMS films, degree of chemical order

For CFMS layer samples without Ag, investigated

properties can be correlated mainly with the surface

For CFGG and Ag-buffered CFMS, it is difficult to separate the surface effects from those related to the

change of chemical order with increasing thickness.

SAMPLE & PREPARATION

L21-CFMS

Co

Si

Fe or Mn

Ultrahigh-vacuum (UHV)-compatible magnetron sputtering deposition

Cr buffer layer deposition at room temperature and annealing at 600°C

Ag layer deposition



MgO/Cr/CFGG



0.03

the

out-of-plane



τοнοκυ

UNIVERSITY







MAGNETIC ANISOTROPY CONSTANT





REFERENCES

[1] O. M. Chumak, A. Nabiałek, R. Żuberek, I. Radelytskyi, T. Yamamoto, T. Seki, K. Takanashi, L. T. Baczewski, H. Szymczak, IEEE Trans. Magn., Vol. 53, Issue 11, 2501906 (2017).

[2] T. Yamamoto, T. Seki, M. Kotsugi, and K. Takanashi, Appl. Phys. Lett., Vol. 108, Issue 15, 152402 (2016).

effects.



Research

Au 5 nm CFMS t nm MgO (001)

t= 15, 30 and 50

Co₂Fe_{0.4}Mn_{0.6}Si

MgO (001) || Cr (001) || CFGG (001) MgO (001) || Cr (001) || CFMS (001)

Co₂FeGa_{0.5}Ge_{0.5}

CFGG t nm

MgO (001)

t= 30 and 50



MgO (001) || Cr (001) || Ag (001) || CFMS (001)



[3] T. Yamamoto, T. Seki, and K. Takanashi, Phys. Rev. B, Vol. 94, Issue 9, 094419 (2016).

Sesja sprawozdawcza Instytutu Fizyki PAN, Warszawa, Polska